

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L12	19	"257"/*.ccls. and amf	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:15
L5	249	"324"/*.ccls. and afm	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:06
L11	13	"438"/*.ccls. and amf	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:15
L3	16	1 and afm	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 16:59
L2	0	1 and amf	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 16:59
L7	1992	250/306.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:10
L8	96	250/306.ccls. and "324"/*.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:14
L1	487	324/719.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:04
L4	399	324/750.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:04

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L15	22	324/765.ccls. and afm	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:26
L14	1	324/765.ccls. and amf	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:19
L6	18	5 and interconnect	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:10
L13	879	amf and sample	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:19
L9	0	amf and semiconducotr	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:14
L10	150	amf and semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/03/10 17:16

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L27	152	(plurality same micro same electro same mechanical same system same cantilevers same apply same voltage same vlsi same circuit same interconnect same without same physical same contact same measuring same component same deflection same characteristics same electrical same force same applied same passed same through).clm.	US-PGPUB	OR	ON	2006/03/10 17:39